

| Parameter | Symbol | Conditions | Values |      |      | Unit |
|-----------|--------|------------|--------|------|------|------|
|           |        |            | min.   | typ. | max. |      |

### Thermal characteristics<sup>2)</sup>

|                                     |            |                                              |   |     |     |     |
|-------------------------------------|------------|----------------------------------------------|---|-----|-----|-----|
| Thermal resistance, junction - case | $R_{thJC}$ | -                                            | - | -   | 4.5 | K/W |
| SMD version, device on PCB          | $R_{thJA}$ | minimal footprint                            | - | 100 | -   |     |
|                                     |            | 6 cm <sup>2</sup> cooling area <sup>3)</sup> | - | 60  | -   |     |

### Electrical characteristics, at $T_j=25\text{ °C}$ , unless otherwise specified

#### Static characteristics

|                                                |               |                                                                 |     |      |     |               |
|------------------------------------------------|---------------|-----------------------------------------------------------------|-----|------|-----|---------------|
| Drain-source breakdown voltage                 | $V_{(BR)DSS}$ | $V_{GS}=0\text{ V}, I_D=1\text{ mA}$                            | 60  | -    | -   | V             |
| Gate threshold voltage                         | $V_{GS(th)}$  | $V_{DS}=V_{GS}, I_D=10\mu\text{A}$                              | 1.2 | 1.7  | 2.2 |               |
| Zero gate voltage drain current <sup>4)</sup>  | $I_{DSS}$     | $V_{DS}=60\text{ V}, V_{GS}=0\text{ V}, T_j=25\text{ °C}$       | -   | 0.01 | 1   | $\mu\text{A}$ |
|                                                |               | $V_{DS}=60\text{ V}, V_{GS}=0\text{ V}, T_j=125\text{ °C}^{2)}$ | -   | 5    | 100 |               |
| Gate-source leakage current <sup>4)</sup>      | $I_{GSS}$     | $V_{GS}=16\text{ V}, V_{DS}=0\text{ V}$                         | -   | -    | 100 | nA            |
| Drain-source on-state resistance <sup>4)</sup> | $R_{DS(on)}$  | $V_{GS}=4.5\text{ V}, I_D=10\text{ A}$                          | -   | 31   | 46  | m $\Omega$    |
|                                                |               | $V_{GS}=10\text{ V}, I_D=17\text{ A}$                           | -   | 21   | 26  |               |

| Parameter | Symbol | Conditions | Values |      |      | Unit |
|-----------|--------|------------|--------|------|------|------|
|           |        |            | min.   | typ. | max. |      |

### Dynamic characteristics<sup>2)</sup>

|                                            |              |                                                                                      |   |      |      |    |
|--------------------------------------------|--------------|--------------------------------------------------------------------------------------|---|------|------|----|
| Input capacitance <sup>4)</sup>            | $C_{iss}$    | $V_{GS}=0\text{ V}, V_{DS}=25\text{ V},$<br>$f=1\text{ MHz}$                         | - | 1100 | 1430 | pF |
| Output capacitance <sup>4)</sup>           | $C_{oss}$    |                                                                                      | - | 300  | 390  |    |
| Reverse transfer capacitance <sup>4)</sup> | $C_{rss}$    |                                                                                      | - | 18   | 36   |    |
| Turn-on delay time                         | $t_{d(on)}$  | $V_{DD}=30\text{ V}, V_{GS}=10\text{ V},$<br>$I_D=20\text{ A}, R_G=11\text{ }\Omega$ | - | 5    | -    | ns |
| Rise time                                  | $t_r$        |                                                                                      | - | 1.5  | -    |    |
| Turn-off delay time                        | $t_{d(off)}$ |                                                                                      | - | 18   | -    |    |
| Fall time                                  | $t_f$        |                                                                                      | - | 10   | -    |    |

### Gate Charge Characteristics<sup>2, 4)</sup>

|                       |               |                                                                            |   |     |     |    |
|-----------------------|---------------|----------------------------------------------------------------------------|---|-----|-----|----|
| Gate to source charge | $Q_{gs}$      | $V_{DD}=48\text{ V}, I_D=20\text{ A},$<br>$V_{GS}=0\text{ to }10\text{ V}$ | - | 4.3 | 5.6 | nC |
| Gate to drain charge  | $Q_{gd}$      |                                                                            | - | 1.7 | 3.4 |    |
| Gate charge total     | $Q_g$         |                                                                            | - | 15  | 20  |    |
| Gate plateau voltage  | $V_{plateau}$ |                                                                            | - | 3.9 | -   | V  |

### Reverse Diode

|                                                                      |               |                                                                         |   |      |     |    |
|----------------------------------------------------------------------|---------------|-------------------------------------------------------------------------|---|------|-----|----|
| Diode continuous forward current <sup>2)</sup><br>one channel active | $I_S$         | $T_C=25\text{ }^\circ\text{C}$                                          | - | -    | 20  | A  |
| Diode pulse current <sup>2)</sup><br>one channel active              | $I_{S,pulse}$ |                                                                         | - | -    | 80  |    |
| Diode forward voltage                                                | $V_{SD}$      | $V_{GS}=0\text{ V}, I_F=17\text{ A},$<br>$T_J=25\text{ }^\circ\text{C}$ | - | 0.95 | 1.3 | V  |
| Reverse recovery time <sup>2)</sup>                                  | $t_{rr}$      | $V_R=30\text{ V}, I_F=I_S,$<br>$di_F/dt=100\text{ A}/\mu\text{s}$       | - | 33   | -   | ns |
| Reverse recovery charge <sup>2, 4)</sup>                             | $Q_{rr}$      |                                                                         | - | 30   | -   | nC |

<sup>1)</sup> Current is limited by bondwire; with an  $R_{thJC} = 4.5\text{K/W}$  the chip is able to carry 26.6A at 25°C.

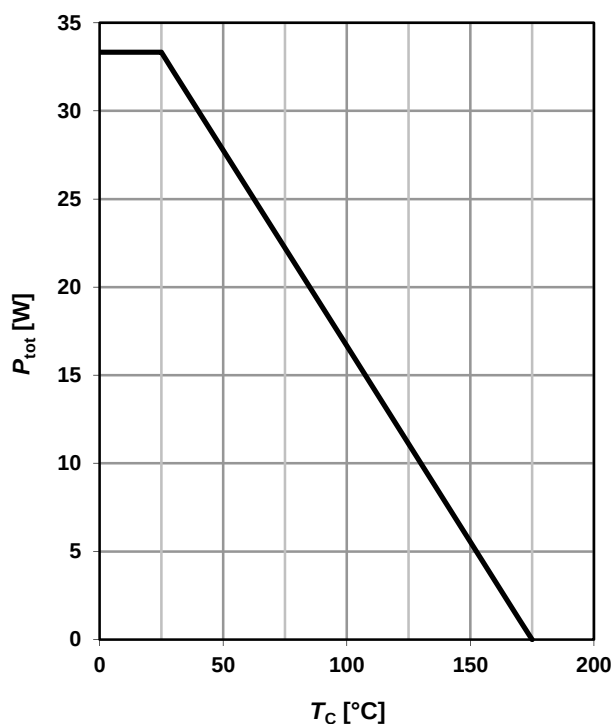
<sup>2)</sup> Specified by design. Not subject to production test.

<sup>3)</sup> Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

<sup>4)</sup> Per channel

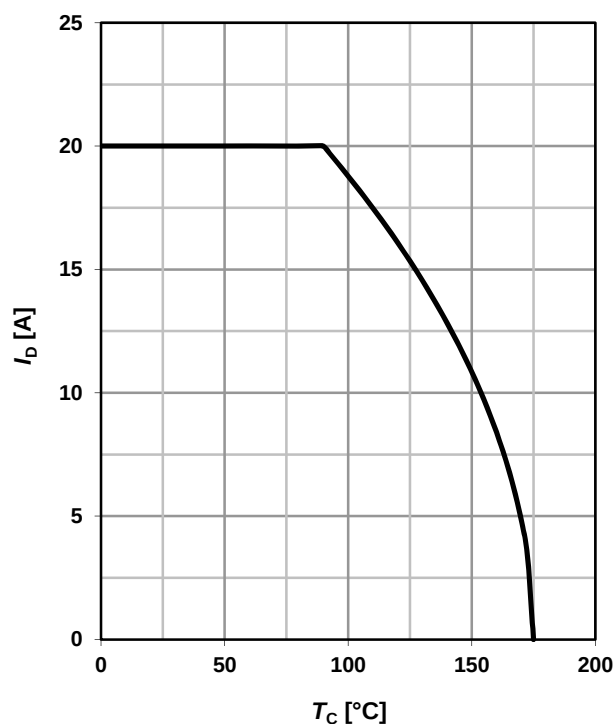
### 1 Power dissipation

$P_{\text{tot}} = f(T_C)$ ;  $V_{\text{GS}} \geq 6 \text{ V}$ ; one channel active



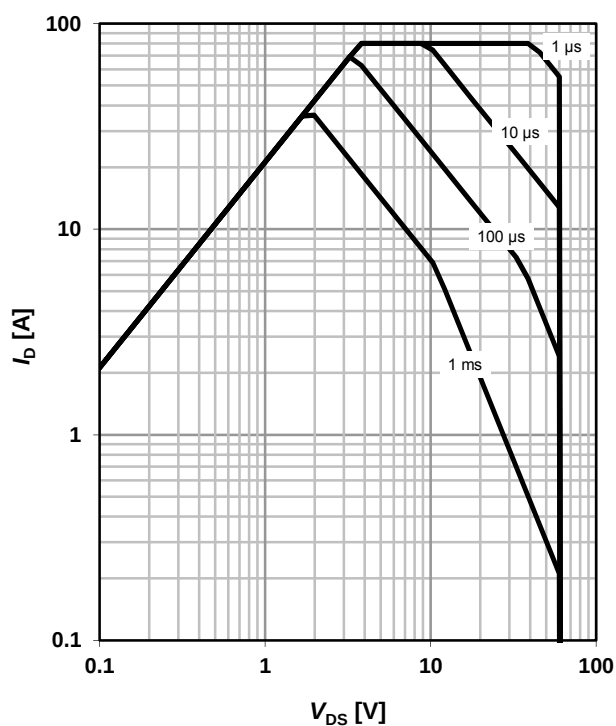
### 2 Drain current

$I_D = f(T_C)$ ;  $V_{\text{GS}} \geq 6 \text{ V}$ ; one channel active



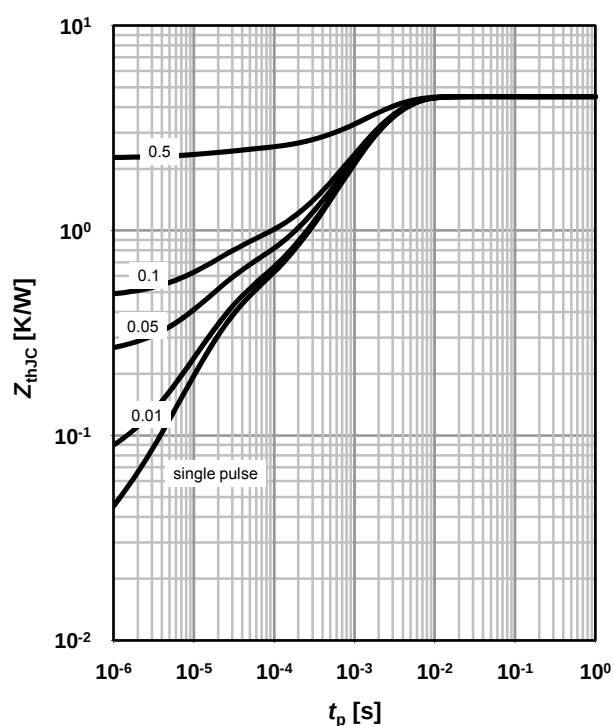
### 3 Safe operating area

$I_D = f(V_{\text{DS}})$ ;  $T_C = 25^\circ\text{C}$ ;  $D = 0$ ; one channel active  
parameter:  $t_p$



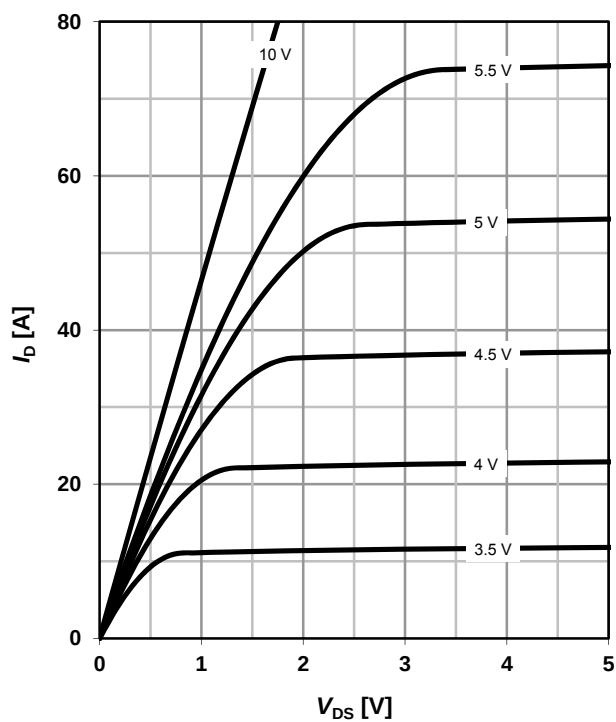
### 4 Max. transient thermal impedance

$Z_{\text{thJC}} = f(t_p)$   
parameter:  $D = t_p/T$



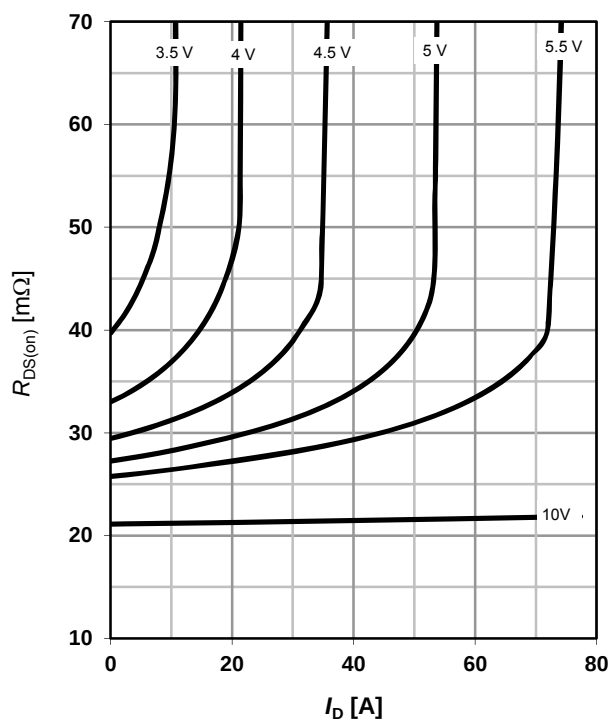
### 5 Typ. output characteristics<sup>4)</sup>

 $I_D = f(V_{DS}); T_j = 25^\circ\text{C}$ 

parameter:  $V_{GS}$ 


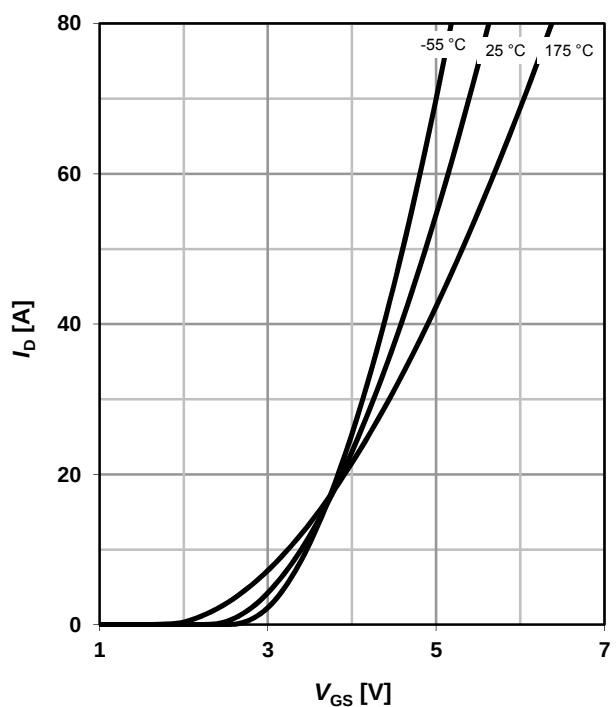
### 6 Typ. drain-source on-state resistance<sup>4)</sup>

 $R_{DS(on)} = f(I_D); T_j = 25^\circ\text{C}$ 

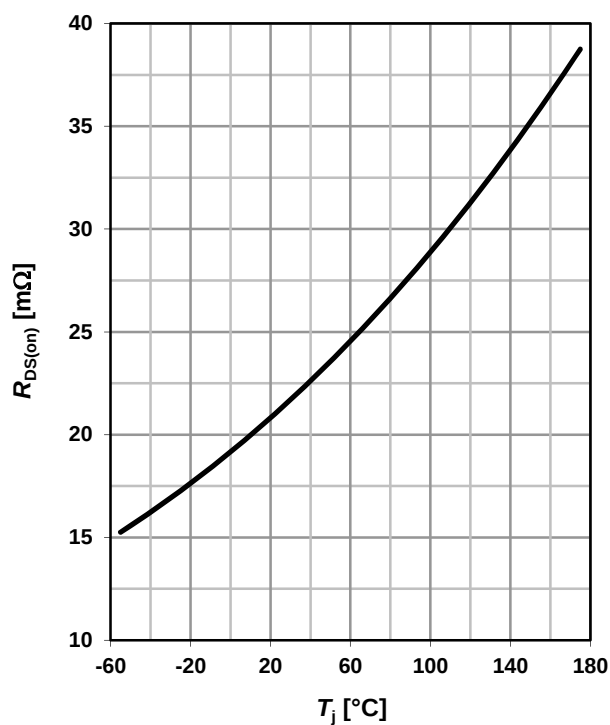
parameter:  $V_{GS}$ 


### 7 Typ. transfer characteristics<sup>4)</sup>

 $I_D = f(V_{GS}); V_{DS} = 6\text{ V}$ 

parameter:  $T_j$ 


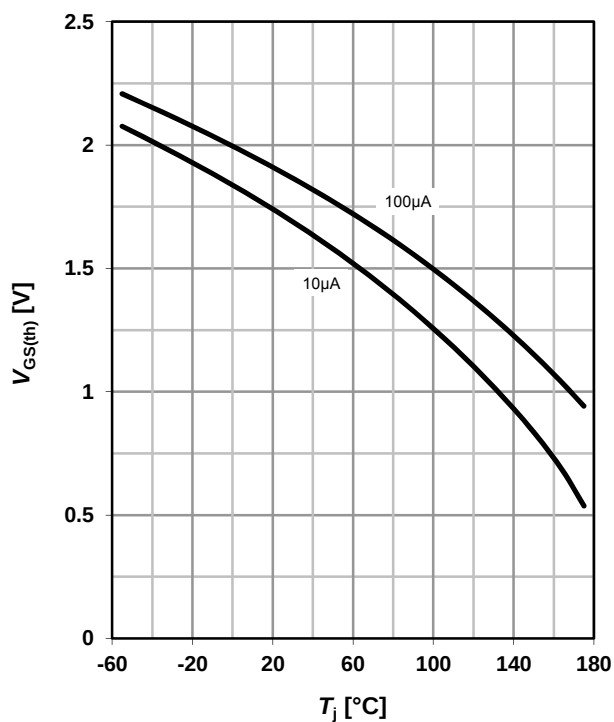
### 8 Typ. drain-source on-state resistance<sup>4)</sup>

 $R_{DS(on)} = f(T_j); I_D = 17\text{ A}; V_{GS} = 10\text{ V}$ 


## 9 Typ. gate threshold voltage

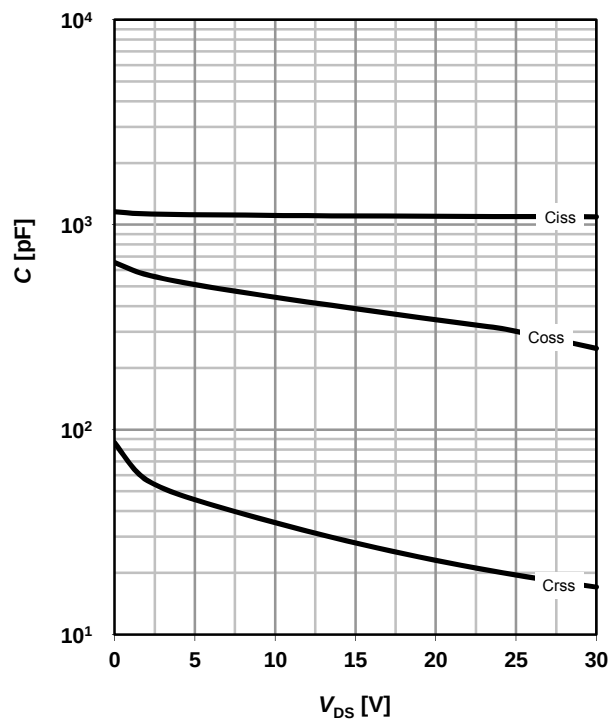
$$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$$

parameter:  $I_D$



## 10 Typ. Capacitances<sup>4)</sup>

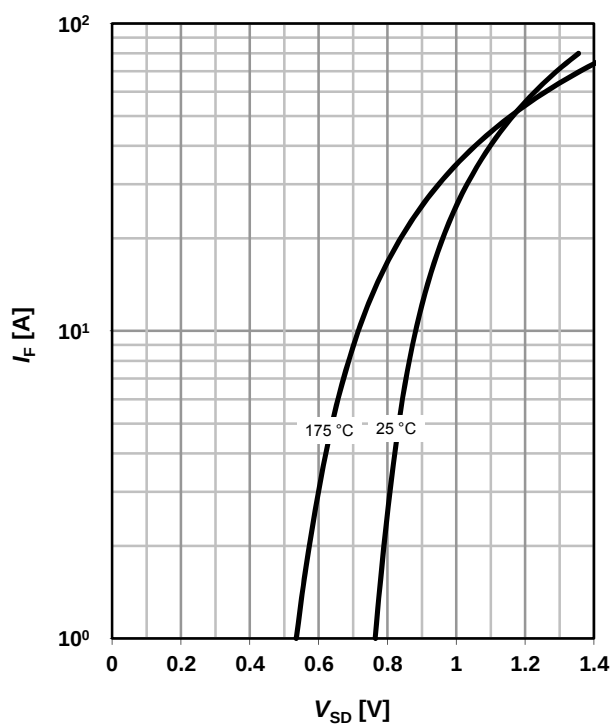
$$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$$



## 11 Typical forward diode characteristics<sup>4)</sup>

$$I_F = f(V_{SD})$$

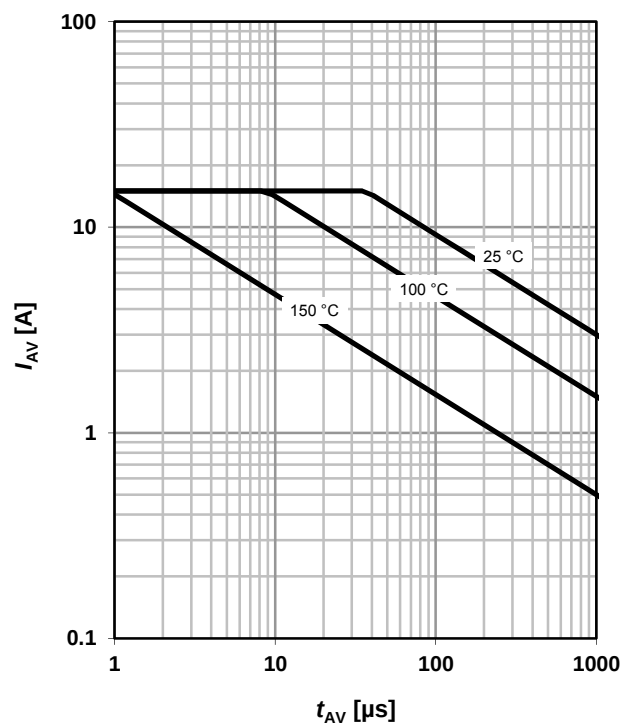
parameter:  $T_j$



## 12 Avalanche characteristics<sup>4)</sup>

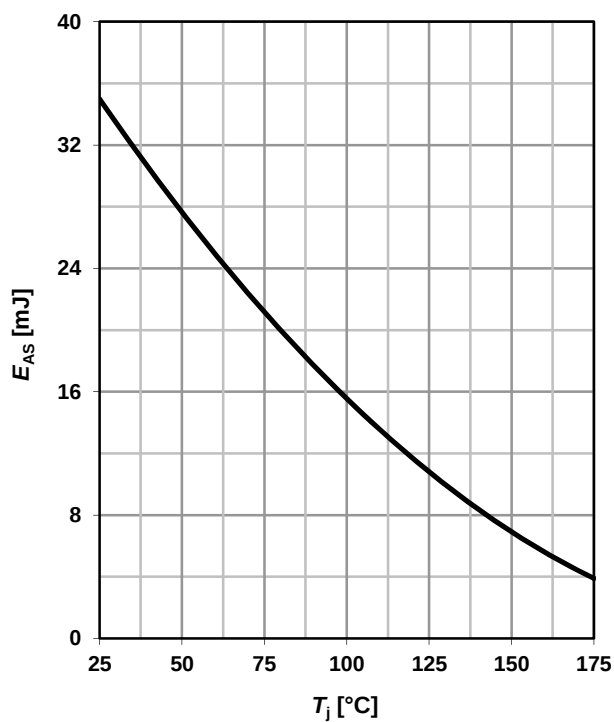
$$I_{AS} = f(t_{AV})$$

parameter:  $T_{j(start)}$



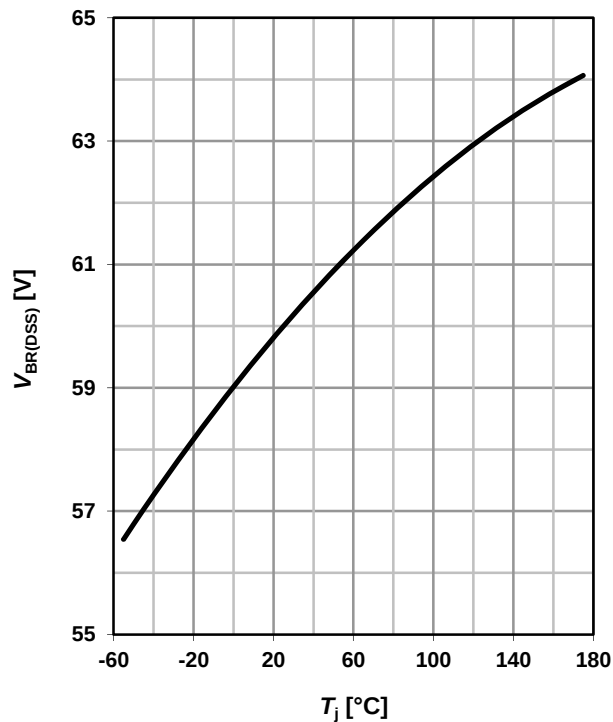
### 13 Avalanche energy<sup>4)</sup>

$$E_{AS} = f(T_j), I_D = 10A$$



### 14 Drain-source breakdown voltage

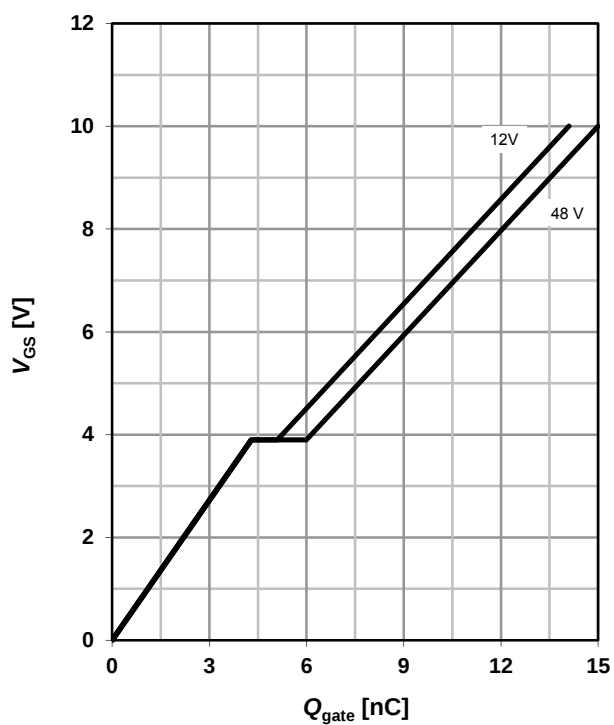
$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$



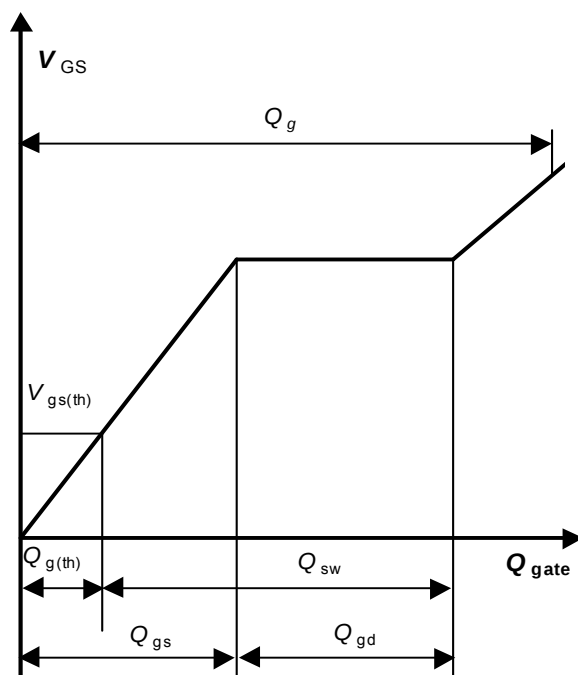
### 15 Typ. gate charge<sup>4)</sup>

$$V_{GS} = f(Q_{gate}); I_D = 20 \text{ A pulsed}$$

parameter:  $V_{DD}$



### 16 Gate charge waveforms



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Revision History

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| Version      | Date       | Changes                 |
|--------------|------------|-------------------------|
| Revision 1.0 | 14.11.2012 | Data Sheet revision 1.0 |
|              |            |                         |
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|              |            |                         |